INTERNATIONAL STANDARD ISO/IEC 10373-3:2010
TECHNICAL CORRIGENDUM 1

Published 2013-09-01

Identification cards — Test methods —

Part 3:
Integrated circuit cards with contacts and related interface devices

TECHNICAL CORRIGENDUM 1:

Cartes d'identification — Méthodes d'essai —

Partie 3: Cartes à circuit(s) intégré(s) à contacts et dispositifs d'interface assimilés

RECTIFICATIF TECHNIQUE 1:

Technical Corrigendum 1 to ISO/IEC 10373-3:2010 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

4.7.2.14 NOTE

Replace the note with

"If a specific functionality is not implemented in the IFD, the IFD-test-apparatus is not required to have the corresponding test-capability (e.g. T=1 protocol not implemented in the IFD)"

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5.1.2 Step e)

Replace

"ISO/IEC 7816-3:2006, 5.3.4"

with

"ISO/IEC 7816-3:2006, 6.3.2".

6.2.2.2 step a)

Replace

"Run the Test Scenario with the card with nominal bit-timing parameters (see ISO/IEC 7816-3:2006,10.2)"

with

"Run the Test Scenario with the card with nominal character-timing parameters (see ISO/IEC 7816-3:2006,7.2)"

6.2.3.2 step d)

Replace

"Repeat a) to b) with every provided etu-factor"

with

"Repeat a) to c) with every provided etu-factor".

8.2.3.2 step e)

Replace

"card-test-apparatus"

with

"IFD-test-apparatus".

Table 68 - Title

Replace

"card test apparatus bit timimg parameters"

with

"IFD test apparatus bit timing parameters"